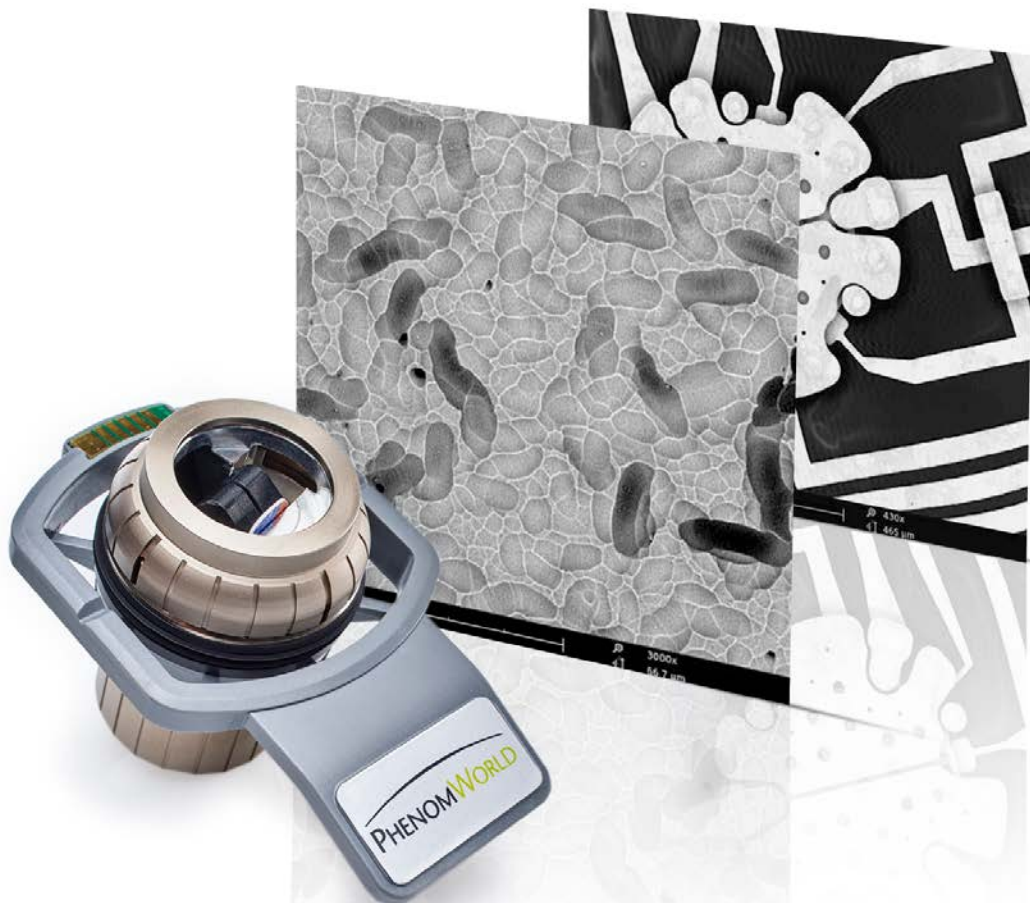


Phenom Sample Holder Inserts

Insertable Sample Holders for fast and easy sample preparation





Sample preparation with micro-electronics insert

The Metallurgical Sample Holder and Metallurgical Charge Reduction Sample Holder can be extended with the Thermo Scientific™ Phenom Micro-Electronics and X-view inserts. These inserts are designed to enable fast sample preparation for specific groups of samples that be examined on the Phenom desktop scanning electron microscope (SEM). They also speed up sample throughput times.

Phenom Micro-Electronics Insert

Imaging micro-electronics, solar cells and other wafer based samples requires non-destructive sample preparation methods that allow the sample to be reused after imaging.

Typically, samples to be viewed or analyzed in an electron microscope are glued onto an aluminum holder. Removing the sample after imaging may cause damage, and contaminate or even break the sample. The micro-electronics insert is designed to overcome this problem. Its unique clamping mechanism makes glue or other adhesives obsolete.

Other commercially available mechanisms use clamps that require surface contact with the sample. This often results in surface damage and obscures part of the sample. The micro-electronics insert does not use surface contact to hold the sample: angled clamping fingers ensure the sample is held down firmly, and the clamping force is evenly spread by the 16 fingers.

- No tools required
- No surface contact
- Easy sample recovery after use
- Preserves original sample state



Sample preparation with X-view insert

Phenom X-view Insert

The X-view insert is used in combination with the metallurgical sample holder. Sample preparation for cross-sectional imaging can be a time consuming process. Samples are often embedded in resin and polished. With the X-view insert, the sample is easily secured in the holder using a split clamping mechanism. The sample position can be adjusted quickly and easily without the need for tools. Imaging the sample using the X-view insert preserves the natural state of the sample, allowing reuse in the production process or in further laboratory investigations.

Image coatings, multi-layer semiconductors and fractured surfaces require X-sectional preparation. Typically, these samples are prepared as a resin mount, a time consuming and labor intensive process. The X-view insert eliminates the need for screws and tools to clamp the sample.

- No tools required
- Easy sample positioning
- Preserves original sample state

Specifications

Micro-Electronics Insert Sample size

- Between 10 mm x 10 mm and 19 mm x 19 mm
- Maximum 1.5 mm thickness

X-view Insert Sample size

- 15 mm x 25 mm (w x l)
- Maximum 10 mm thickness

Find out more at thermofisher.com/phenomworld